

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OHNO ET AL.	
		Examiner JONATHAN HAN	Art Unit 2818	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-4,103,315 A	07-1978	Hempstead et al.	360/110
*	B US-5,294,287 A	03-1994	Chang et al.	117/88
*	C US-5,390,061 A	02-1995	Nakatani et al.	360/324.2
*	D US-5,734,605 A	03-1998	Zhu et al.	365/173
*	E US-5,768,181 A	06-1998	Zhu et al.	365/158
*	F US-2001/0007532 A1	07-2001	Sato et al.	365/173
*	G US-6,456,467 B1	09-2002	Mao et al.	360/319
*	H US-2003/0209770 A1	11-2003	Flatte et al.	257/421
*	I US-5,835,003	11-1998	Nickel et al.	338/32R
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.